



NOTES

1. REFLECTION CUTOFF, TRANSMISSION START WAVELENGTH: 780 nm
2. CLEAR APERTURE: $>90\%CA$
3. SURFACE QUALITY(S1, S2): $40/20(S/D)$
4. WAVEFRONT ERROR(RMS): $\lambda/4@633\text{ nm}$
5. PARALLELISM(S1, S2): $<3\text{ arcmin}$
6. COATING:
 - FILTER COATING(S1): $T_{\text{abs}}>85\%, T_{\text{avg}}>90\%@550-788\text{ nm}, 45^\circ\text{ AOI}$
 $R_{\text{abs}}>90\%, R_{\text{avg}}>95\%@825-1100\text{ nm}, 45^\circ\text{ AOI}$
 - AR COATING(S2): $R_{\text{abs}}<0.8\%@550-788\text{ nm}, 45^\circ\text{ AOI}$
7. CHAMFER: $<0.35\text{ mm}, 45^\circ$

DRAWING PROJECTION			LBTEK			
	NAME	DATE				
DRAWN	LZHOU	JUL./30th/24	SHORTWAVE DICHOIC MIRROR $\phi 25.4\text{ mm} \times 3.2\text{ mm}, 780\text{ nm}$			
APPROVAL	WCHENG	JUL./30th/24	MATERIAL	WEIGHT	SCALE	REV
FOR INFORMATION ONLY NOT FOR MANUFACTURING PURPOSES			UVFS	3.6 g	1:1	A